

May 2008

FDMC8884

N-Channel Power Trench[®] MOSFET 30V, 15A, 19m Ω

Features

- Max $r_{DS(on)} = 19m\Omega$ at $V_{GS} = 10V$, $I_D = 9.0A$
- Max $r_{DS(on)} = 30m\Omega$ at $V_{GS} = 4.5V$, $I_D = 7.2A$
- High performance trchnology for extremely low r_{DS(on)}
- Termination is Lead-free and RoHS Compliant



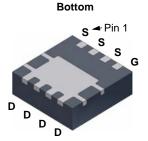
General Description

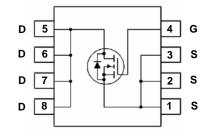
This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance. This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.

Application

- High side in DC DC Buck Converters
- Notebook battery power management
- Load switch in Notebook







Power 33

MOSFET Maximum Ratings $T_A = 25$ °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V_{DS}	Drain to Source Voltage			30	V
V_{GS}	Gate to Source Voltage			±20	V
	Drain Current -Continuous (Package limited)	T _C = 25°C		15	
	-Continuous (Silicon limited)	T _C = 25°C		24	A
ID	-Continuous	T _A = 25°C	(Note 1a)	9.0	A
	-Pulsed			40	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	24	mJ
D	Power Dissipation	T _C = 25°C		18	W
P_{D}	Power Dissipation	T _A = 25°C	(Note 1a)	2.3]
T _J , T _{STG}	Operating and Storage Junction Temperature R	ange		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case		6.6	°C/W
R _{e.IA}	Thermal Resistance, Junction to Ambient (N	lote 1a)	53	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC8884	FDMC8884	Power 33	13"	12mm	3000 units

Electrical Characteristics $T_J = 25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250μA, referenced to 25°C		22		mV/°C
l	Zero Gate Voltage Drain Current	V _{DS} = 24V, V _{GS} = 0V			1	
IDSS	Zero Gate Voltage Drain Gurrent	$T_J = 125$ °C			250	μΑ
I_{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250 \mu A$	1.2	1.9	2.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 250μA, referenced to 25°C		-6		mV/°C
		$V_{GS} = 10V, I_D = 9.0A$		16	19	
r _{DS(on)}	r _{DS(on)} Static Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 7.2A$		22	30	mΩ
		$V_{GS} = 10V, I_D = 9.0A, T_J = 125^{\circ}C$		22	30	
g _{FS}	Forward Transconductance	$V_{DD} = 5V, I_{D} = 9.0A$		24		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45V V 0V	513	685	рF
C _{oss}	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$ $f = 1MHz$	110	150	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/12	76	115	pF
R_g	Gate Resistance	f = 1MHz	1.4	2.1	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		6	12	ns
t _r	Rise Time	$V_{DD} = 15V, I_D = 9.0A,$	2	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 6\Omega$	15	27	ns
t _f	Fall Time		2	10	ns
0	Total Gate Charge	V _{GS} = 0V to 10V	10	14	nC
$Q_{g(TOT)}$	Total Gate Charge	$V_{GS} = 0V \text{ to } 4.5V V_{DD} = 15V$	5.0	7.0	nC
Q_{gs}	Total Gate Charge	I _D = 9.0A	1.8		nC
Q_{gd}	Gate to Drain "Miller" Charge		2.2		nC

Drain-Source Diode Characteristics

V _{SD} Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = 9.0A$ (Note 2)		0.86	1.2	\/	
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = 1.6A$ (Note 2)		0.76	1.2	V
t _{rr}	Reverse Recovery Time	I _E = 9.0A. di/dt = 100A/us		13	18	ns
Q _{rr}	Reverse Recovery Charge	T _F = 9.0A, αι/αι = 100A/μs		3	10	nC

NOTES

^{1.} R_{0JA} is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a. 53°C/W when mounted on a 1 in² pad of 2 oz copper



b. 125°C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300μ s, Duty cycle < 2.0%.
- 3. Starting $T_J = 25^{o}C$; N-ch: L = 1mH, $I_{AS} = 7A$, $V_{DD} = 30V$, $V_{GS} = 10V$.

Typical Characteristics $T_J = 25$ °C unless otherwise noted

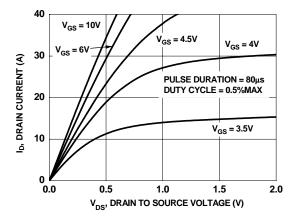


Figure 1. On-Region Characteristics

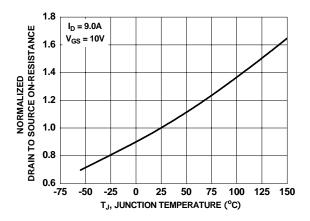


Figure 3. Normalized On-Resistance vs Junction Temperature

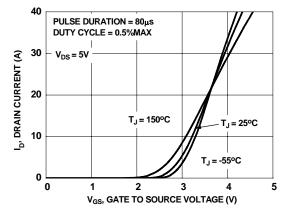


Figure 5. Transfer Characteristics

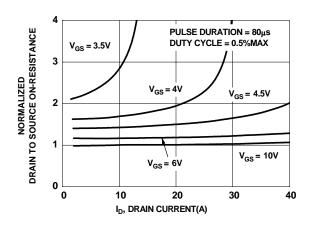


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

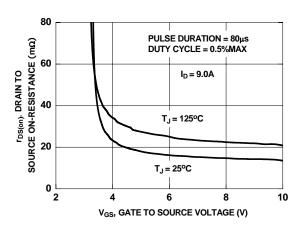


Figure 4. On-Resistance vs Gate to Source Voltage

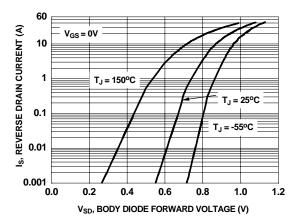


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

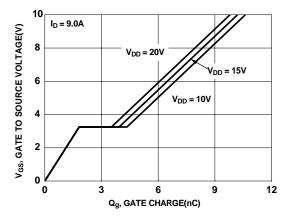


Figure 7. Gate Charge Characteristics

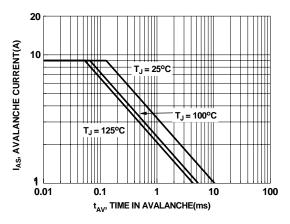


Figure 9. Unclamped Inductive Switching Capability

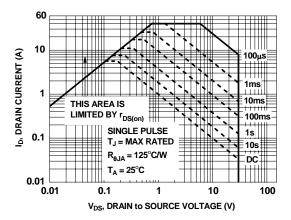


Figure 11. Forward Bias Safe Operating Area

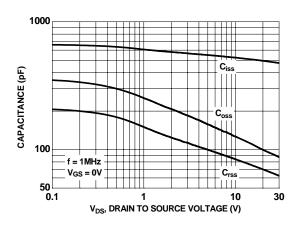


Figure 8. Capacitance vs Drain to Source Voltage

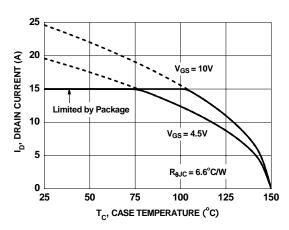


Figure 10. Maximum Continuous Drain Current vs Case Temperature

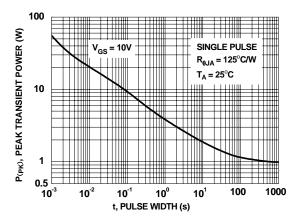


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25°C unless otherwise noted

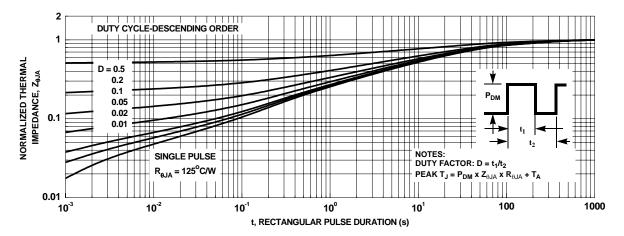


Figure 13. Transient Thermal Response Curve

Dimensional Outline and Pad Layout -3.30±0.10 -2.37 MIN SYM PKG Ė -(0.45) 8 5 2.15 MIN (0.40)PKG Q-PKGÇ 3.30 ± 0.10 (0.65) \bigcirc 0.70 MIN 4 1 0.65 -0.42 MIN SEE DETAIL A 1.95 LAND PATTERN RECOMMENDATION 1.95 0.65 0.32 ± 0.05 ⊕ 0.10 C A B -0.40 ± 0.10 (0.20) $\mathsf{PKG}\, \varsigma$ 2.00 ± 0.10 $(0.39)^{\frac{1}{3}}$ 8 (2.27) -NOTES: UNLESS OTHERWISE SPECIFIED (0.52)PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. BA, DATED OCTOBER 2002. 0.10 C ALL DIMENSIONS ARE IN MILLIMETERS. DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR 1.10 BURRS DOES NOT EXCEED 0.10MM. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994. DRAWING FILE NAME: PQFN08BREV1 △ 0.08 C 0.05 С 0.20 ± 0.025 SEATING PLANE DETAIL A PQFN08BREV1





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Rev. I34